

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/660,957	HAYES ET AL.
	Examiner	Art Unit
	Ellen C. Tran	2134

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	2/16/2007	ECT
NPL - IEEE XPLORE	2/16/2007	ECT
INVENTOR SEARCH - PALM/eDAN	2/16/2007	ECT
All claims were reviewed for 101 rejections	2/16/2007	ECT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner